



Advancement of Fault Detection and Fault-Tolerant Control with Applications

Guest Editors:

Prof. Dr. Nantian Huang

School of Electrical Engineering,
Northeast Electric Power
University, Jilin, China

Prof. Dr. Zhenbing Zhao

School of Electrical and
Electronic Engineering, North
China Electric Power University,
Baoding 071003, China

Dr. Shu Zhang

Electrical Engineering
Department, Sichuan University,
Chengdu, China

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Message from the Guest Editors

Dear Colleagues,

At present, with the development of artificial intelligence technology, big data mining, machine learning, deep learning, and other technologies, a large number of fault detection methods and applications as well as fault-tolerant control methods have been gradually proposed. However, these methods face challenges regarding their field application and reliability. This Special Issue aims to present research and analysis on fault detection and fault-tolerant control. This includes but is not limited to:

- Rotating machinery monitoring and vibration signal processing
- Measurement methods, technologies, and systems for equipment signals
- Fault-tolerant control
- Fault diagnosis based on interpretable deep learning
- Enhanced technology for equipment failure data
- Multi-sensor data fusion fault diagnosis
- Fault detection under unbalanced small sample conditions
- Field application effect analysis of equipment status detection method





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Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

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MDPI, St. Alban-Anlage 66
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